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Micro/Nano Optical Imaging Technologies and Applications

Min Gu
Xiacong Yuan
Min Qiu
Editors

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Introduction

We have had the great honor of organizing the Fifth International Symposium on Photoelectronic Detection and Imaging (ISPD1) in Beijing. It was truly a great pleasure for us to greet the more than 1,200 participants from many different countries attending ISPD1 2013! I firmly believe that the symposium will become an important international event in the field of photoelectronic detection and imaging technology.

ISPD1 2013 was sponsored by SPIE, The Optical Society, European Optical Society, and the Chinese Society of Astronautics, and was organized by the Photoelectronic Technology Committee, Chinese Society of Astronautics, Tianjin Jinhang Institute of Technical Physics, Science and Technology on Low Light Level Night Vision Laboratory, Science and Technology on Optical Radiation Lab. and Science and Technology on Electromagnetic Scattering Lab. There were 26 cooperating organizations that supported the meeting. Nearly 850 papers were accepted for presentation at ISPD1 2013, contributed by over 1,370 authors from more than 10 countries, including the United States, United Kingdom, Germany, France, Norway, Australia, Canada, Japan, Korea, Russia, China, and so on. We had seven plenary speeches and 135 famous scientists and experts from home and abroad to present the invited talks at 10 different conferences.

The purpose of ISPD1 2013 is to provide a forum for the participants to report and review the innovative ideas and up-to-date progress and developments, and discuss the novel approaches to applications in the field of photoelectronic detection and imaging. It is sincerely hoped that the research and developments in optical and photoelectronic fields will be promoted, and that international cooperation and the sharing of common interests will be enhanced.

On behalf of Prof. Konstantin Vodopyanov, and the other conference chairs, and the Organization Committee of ISPD1, I would like to heartily thank our sponsors and cooperating organizations for all they have done for the meeting. Thanks also to all the authors for their contributions to the proceedings, to all of the participants and friends for their interest and efforts in helping us make the symposium possible, to the Program Committee for their effective work and valuable advice, and especially the ISPD1 2013 Secretariat and the SPIE staff for their tireless effort and outstanding service in preparing the meeting and publishing the conference proceedings.

Guofan Jin